# A5G26S004N Airfast RF Power GaN Transistor

Rev. 2 — January 2022

This 24 dBm RF power GaN transistor is designed for cellular base station applications covering the frequency range of 2496 to 2690 MHz.

### 2600 MHz

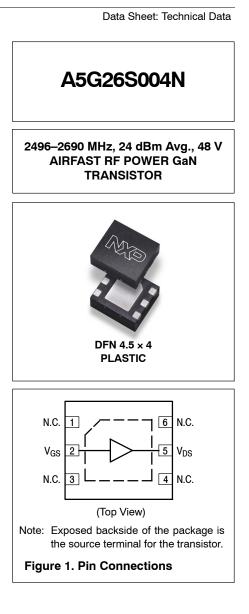
• Typical Single- Carrier W- CDMA Reference Circuit Performance:  $V_{DD}$  = 48 Vdc,  $I_{DQ}$  = 10 mA,  $P_{out}$  = 24 dBm Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF.<sup>(1)</sup>

Frequency	G <sub>ps</sub> (dB)	η <sub>D</sub> (%)	Output PAR (dB)	ACPR (dBc)
2515 MHz	18.7	18.8	10.2	-39.6
2595 MHz	19.6	20.5	9.8	-42.0
2675 MHz	18.9	20.6	9.7	-44.7

1. All data measured in reference circuit with device soldered to printed circuit board.

# Features

- · High terminal impedances for optimal broadband performance
- · Designed for low complexity analog or digital linearization systems
- Universal broadband driver
- · Optimized for massive MIMO active antenna systems for 5G base stations





# Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DSS</sub>	125	Vdc
Gate- Source Voltage	V <sub>GS</sub>	-8, 0	Vdc
Operating Voltage	V <sub>DD</sub>	55	Vdc
Maximum Forward Gate Current @ T <sub>C</sub> = 25°C	I <sub>GMAX</sub>	0.74	mA
Storage Temperature Range	T <sub>stg</sub>	-65 to +150	°C
Case Operating Temperature Range	T <sub>C</sub>	-55 to +150	°C
Maximum Channel Temperature	Т <sub>СН</sub>	225	°C

### **Table 2. Recommended Operating Conditions**

Rating	Symbol	Value	Unit
Operating Voltage	V <sub>DD</sub>	48	Vdc

### Table 3. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 115°C, $P_{D}$ = 1.1 W	R <sub>θJC</sub> (IR)	9.5 (1)	°C/W
Thermal Resistance by Finite Element Analysis, Channel- to- Case Case Temperature 115°C, $P_D$ = 1.1 W	R <sub>θCHC</sub> (FEA)	32 (2)	°C/W

### **Table 4. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JS- 001- 2017)	1B
Charge Device Model (per JS- 002- 2014)	C3

# Table 5. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD22-A113, IPC/JEDEC J-STD-020	3	260	°C

Table 6. Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
Off Characteristics					
Off- State Drain Leakage (V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = -8 Vdc)	I <sub>D(BR)</sub>	_	—	0.74	mAdc
On Characteristics					
Gate Threshold Voltage (V <sub>DS</sub> = 10 Vdc, I <sub>D</sub> = 0.74 mAdc)	V <sub>GS(th)</sub>	-4.9	-2.6	-1.9	Vdc
Gate Quiescent Voltage (V <sub>DD</sub> = 48 Vdc, I <sub>D</sub> = 10 mAdc, Measured in Functional Test)	V <sub>GS(Q)</sub>	-2.9	-2.5	-2.0	Vdc
Gate- Source Leakage Current (V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = -12 Vdc)	I <sub>GSS</sub>	-0.74	_	—	mAdc

1. Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.

R<sub>6CHC</sub> (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated by the expression MTTF (hours) = 10<sup>[A + B/(T + 273)]</sup>, where *T* is the channel temperature in degrees Celsius, *A* = -11.1 and *B* = 8366.

(continued)

# Table 6. Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted) (continued)

Table 0. Lie circal characteristics ( $T_A = 25$ C unless otherwise hole		suj				
Characteristic	Symbol	Min	Тур	Мах	Unit	
<b>Functional Tests (1)</b> (In NXP Production Test Fixture, 50 ohm system) V <sub>DD</sub> = 48 Vdc, I <sub>DQ</sub> = 10 mA, P <sub>out</sub> = 24 dBm Avg., f = 2690 MHz, 1-tone CW.						
Power Gain	G <sub>ps</sub>	18.0	20.9	24.0	dB	
Drain Efficiency	η <sub>D</sub>	20.0	22.4	—	%	
Pout @ 6 dB Compression Point	P6dB	35.0	37.4	—	dBm	
<b>Wideband Ruggedness <sup>(2)</sup> (In NXP Reference Circuit, 50 ohm system)</b> I <sub>D</sub> with 10 dB PAR	<sub>Q</sub> = 10 mA, f =	2595 MHz, A	dditive White	Gaussian No	ise (AWGN)	
ISBW of 400 MHz at 55 Vdc, 0.64 W Avg. Modulated Output Power (3 dB Input Overdrive from 0.3 W Avg. Modulated Output Power)		No D	evice Degrad	ation		

### Typical Performance <sup>(2)</sup> (In NXP Reference Circuit, 50 ohm system) V<sub>DD</sub> = 48 Vdc, I<sub>DQ</sub> = 10 mA, 2515–2675 MHz Bandwidth

	1				
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW <sub>res</sub>	_	250		MHz
Gain Flatness in 160 MHz Bandwidth @ P <sub>out</sub> = 24 dBm Avg.	G <sub>F</sub>	_	0.9	_	dB
Fast CW, 27 ms Sweep					
Pout @ 6 dB Compression Point	P6dB	—	4.0	—	W
AM/PM (Maximum value measured at the P6dB compression point across the 2515–2675 MHz bandwidth)	Φ	—	-16	_	o
Gain Variation over Temperature (-40°C to +85°C)	ΔG		0.012		dB/°C
Output Power Variation over Temperature (-40°C to +85°C)	∆P6dB	_	0.002		dB/°C

### Table 7. Ordering Information

Device	Tape and Reel Information	Package
A5G26S004NT6	T6 Suffix = 5,000 Units, 12 mm Tape Width, 13- inch Reel	DFN 4.5 × 4

1. Part internally input matched.

2. All data measured in reference circuit with device soldered to printed circuit board.

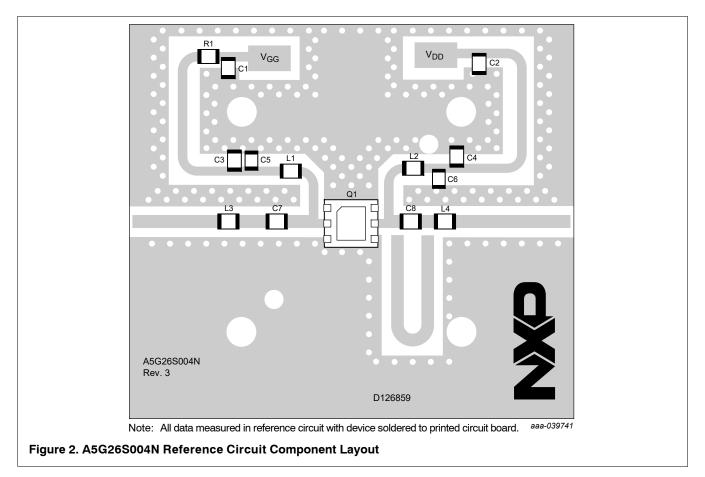
# NOTE: Correct Biasing Sequence for GaN Depletion Mode Transistors

### **Turning the device ON**

- 1. Set  $V_{GS}$  to the pinch- off voltage, typically –5 V.
- 2. Turn on  $V_{\text{DS}}$  to nominal supply voltage (+48 V).
- 3. Increase V<sub>GS</sub> until I<sub>DS</sub> current is attained.
- 4. Apply RF input power to desired level.

### **Turning the device OFF**

- 1. Turn RF power off.
- 2. Reduce V<sub>GS</sub> down to the pinch-off voltage, typically -5 V.
- 3. Adjust drain voltage  $V_{DS}$  to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Turn off V<sub>GS</sub>.



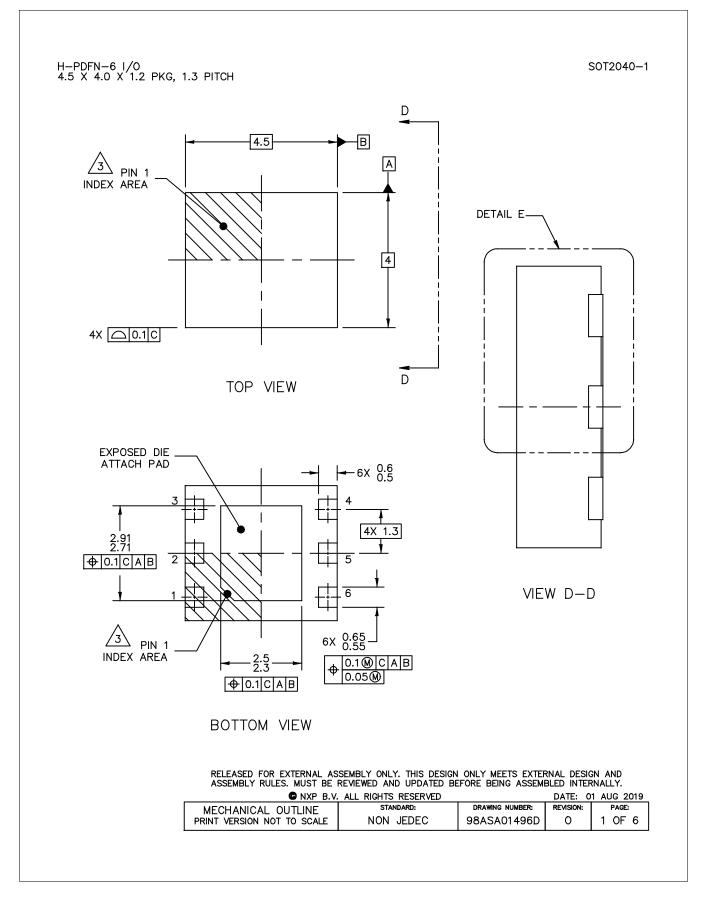
# Table 8. A5G26S004N Reference Circuit Component Designations and Values

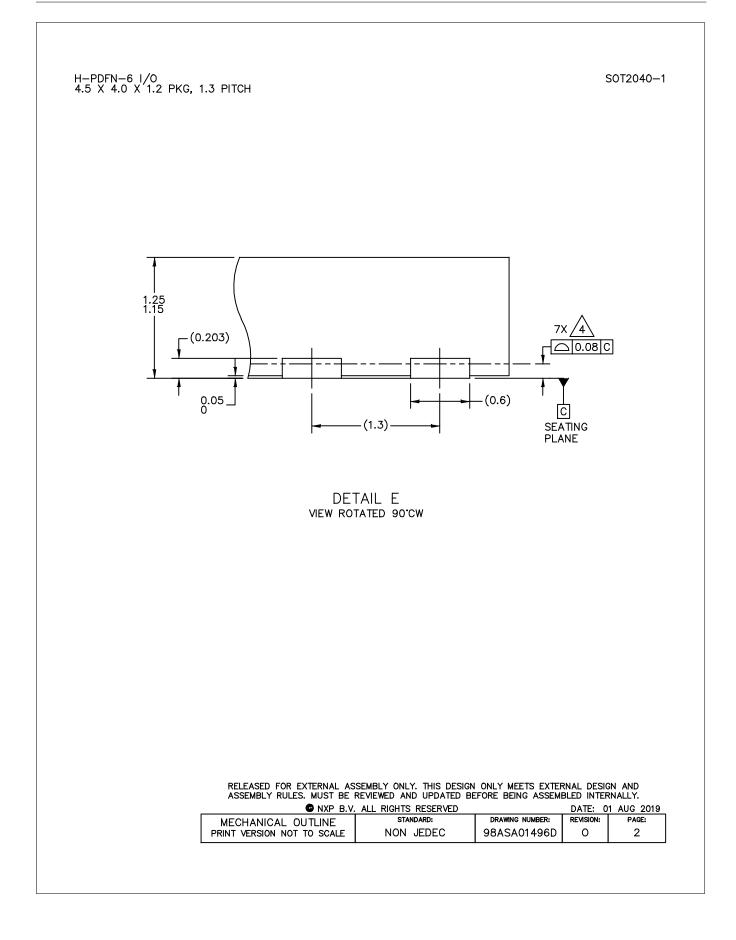
Part	Description	Part Number	Manufacturer
C1, C2	2.2 µF Chip Capacitor	GRM32ER72A225KA35L	Murata
C3, C4	1 μF Chip Capacitor	GRM31MR71H105KA88L	Murata
C5, C6, C7, C8	8.2 pF Chip Capacitor	GQM2195C2E8R2BB12D	Murata
L1	3.9 nH Chip Inductor	0603HP-3N9XJLW	Coilcraft
L2, L3	1.6 nH Chip Inductor	0603HP-1N6XJLW	Coilcraft
L4	4.7 nH Chip Inductor	0603HP-4N7XJLW	Coilcraft
Q1	RF Power GaN Transistor	A5G26S004N	NXP
R1	10 Ω, 1/8 W Chip Resistor	CRCW080510R0FKEA	Vishay
РСВ	Rogers RO4350B, 0.020", $\epsilon_r = 3.66$	D126859	MTL

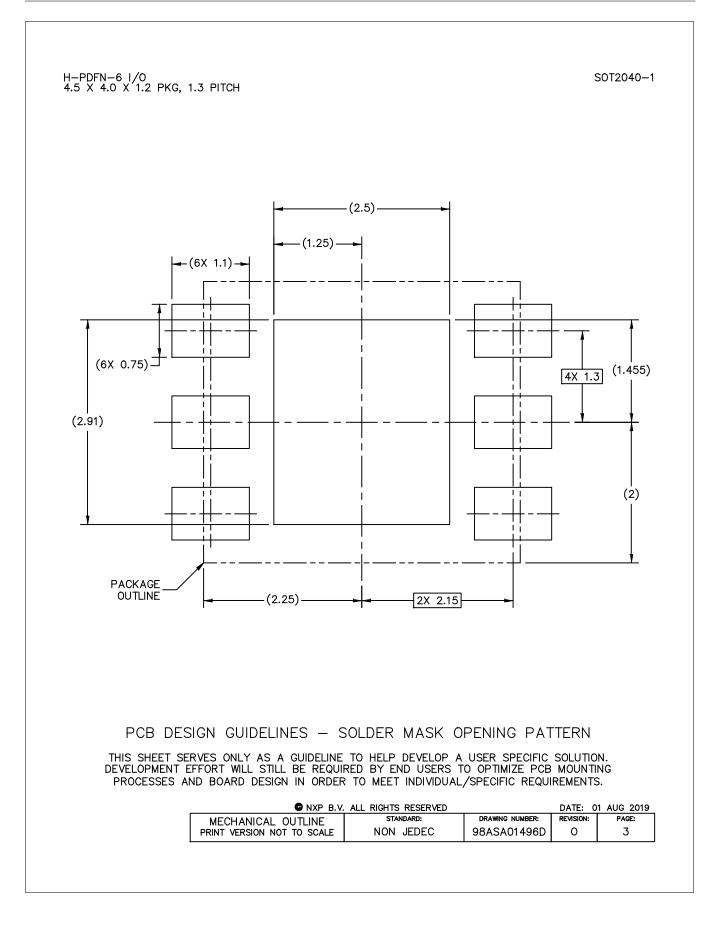


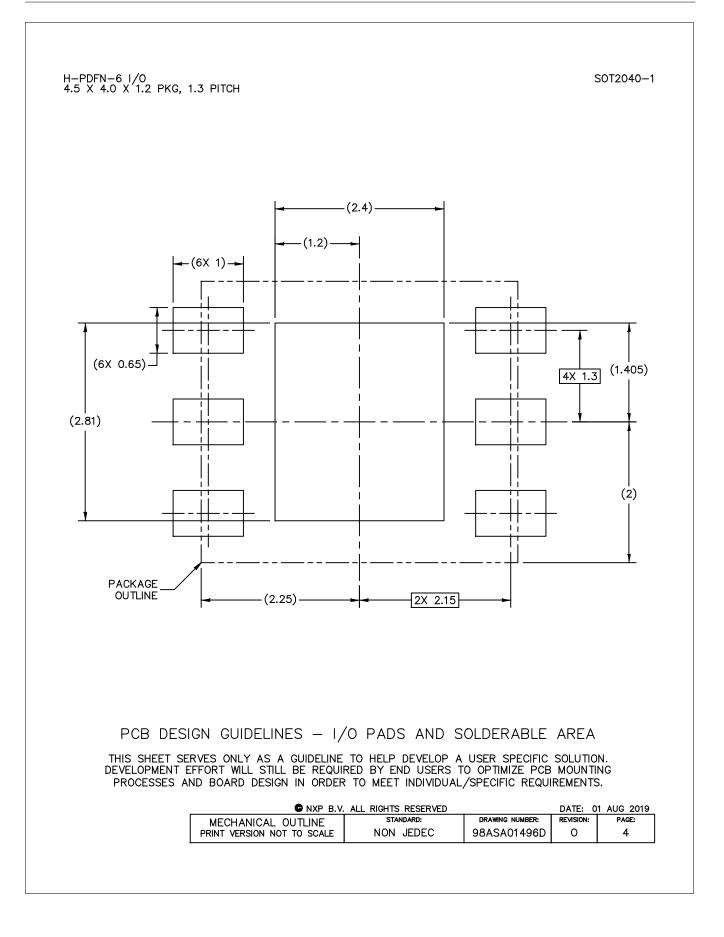
Figure 3. Product Marking

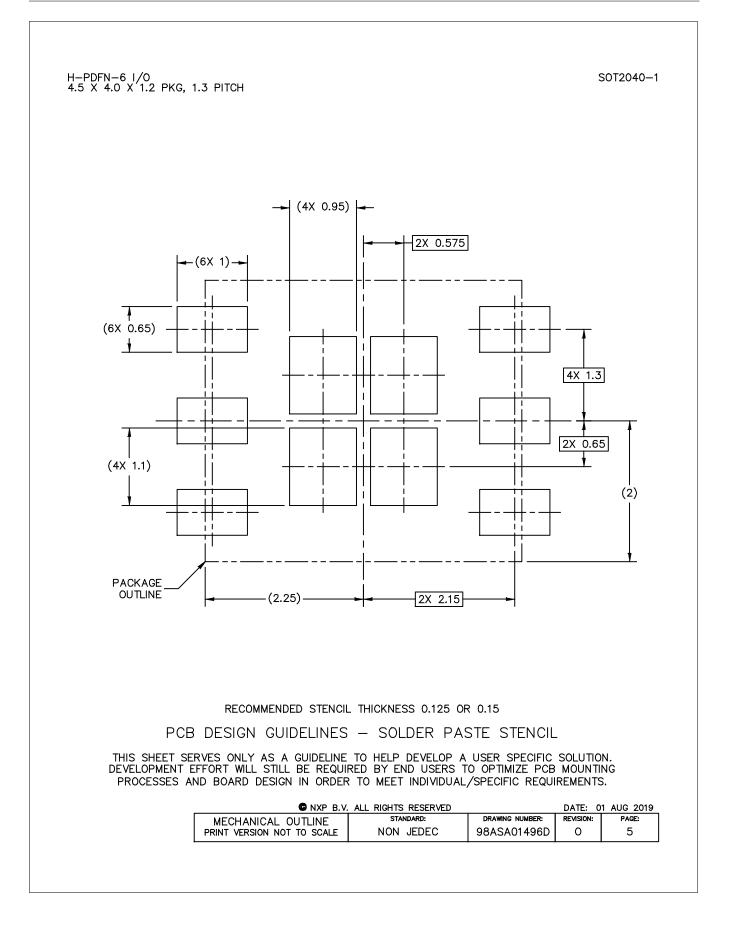
# **Package Information**











H-PDFN-6 I/0 4.5 X 4.0 X 1.2 PKG, 1.3 PITCH

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.

4. COPLANARITY APPLIES TO LEADS AND DIE ATTACH FLAG.

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S0T2040-1

# **Product Documentation, Software and Tools**

Refer to the following resources to aid your design process.

# **Application Notes**

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

# Software

• .s2p File

# **Development Tools**

• Printed Circuit Boards

# **Revision History**

The following table summarizes revisions to this document.

Revision	Date	Description
0	Dec. 2020	Initial release of data sheet
1	Jan. 2021	<ul> <li>Table 1, Maximum Ratings: updated operating voltage for complete data sheet standardization, p. 2</li> <li>Table 2, Recommended Operating Conditions: added to data sheet, p. 2</li> </ul>
2	Jan. 2022	<ul> <li>Table 6, DC On Characteristics, V<sub>GS(th)</sub>: Min, Typ and Max values updated to match production test values, p. 2</li> </ul>

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